

TWO WEBINARS ON NANOMETROLOGY

Instrumentation 7.12.2023

Webinar on nanometrology instrumentation, especially on high-speed long-range scanning probe microscopes (SPM).

Preliminary program (subject to change):

December 7, 2023, 9:00 – 11:30 (CET)

MetExSPM project: Development of traceable methods for high-speed and large-range SPM	<i>Virpi Korpelainen</i> , VTT Technical Research Centre of Finland
Active cantilevers for scanning probe microscopes	<i>Ivo Rangelow</i> , nano analytik GmbH
A high-speed large-range SPM scanner based on a magnetic levitation stage and piezo scanners	<i>Rudolf Krueger</i> , Physik Instrumente (PI) GmbH
Data processing in metrological high-speed scanning probe microscopes	<i>Petr Klapetek</i> , CMI Czech Metrology Institute
A high-speed large-range SPM prototype	<i>Jan Thiesler</i> , PTB Physikalisch-Technische Bundesanstalt
Nanopositioning and nanomeasuring machines	<i>Eberhard Manske</i> , Technische Universität Ilmenau
Grating pitch data evaluation methods – good parameter choices and accuracy	<i>David Nečas</i> , CEITEC, Brno University of Technology

Microsoft Teams meeting

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Applications 8.1.2024

Webinar on applications of nanometrology and scanning probe microscopes (SPM).

Preliminary program (subject to change):

January 8, 2024, 9:00 – 11:30 (CET)

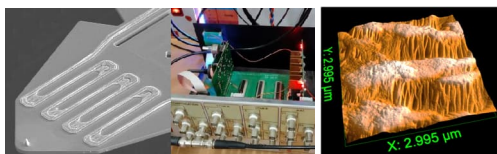
MetExSPM project: Development of traceable methods for high-speed and large-range SPM	<i>Virpi Korpelainen</i> , VTT Technical Research Centre of Finland
Application of nanometrology to improve nanopositioning stages in high-speed AFM	<i>Edward Heaps</i> , NPL National Physical Laboratory
Traceable surface and nanometrology: nanopositioning & nanomeasuring machine at PTB	<i>Gaoliang Dai</i> , PTB Physikalisch-Technische Bundesanstalt
Application of active piezoresistive cantilevers in high-eigenmode surface imaging	<i>Teodor Gotszalk</i> , Wrocław University of Science and Technology
Implementation of interferometers in a commercial SPM to extend positioning capabilities	<i>Bruno Sauvet</i> , VTT Technical Research Centre of Finland
Compressed sensing method for scanning probe microscopy based on Gaussian processes	<i>Radek Šlesinger</i> , CMI Czech Metrology Institute
Applications of open hardware Gwyscope controller for adaptive and high-speed SPM	<i>Miroslav Valtr</i> , CMI Czech Metrology Institute

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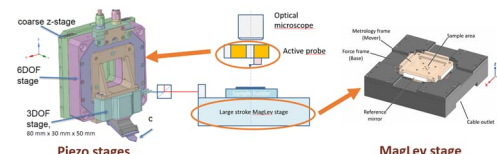
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MetExSPM will turn high-speed SPMs from qualitative imaging devices to high-accuracy quantitative instruments by developing:

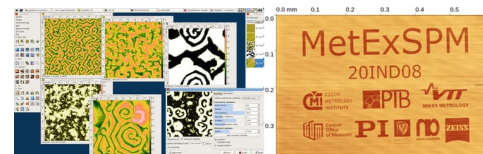
Novel multifunctional probes and electronics



High-speed large stroke scanning stages



Software and advanced scanning strategies



Validated and traceable high-speed SPM

